

APPLICATION DATA SHEET

Electronic Version v14
Stylesheet Version v14.0

Title of Invention	METHOD TO SELECTIVELY CORRECT CRITICAL DIMENSION ERRORS IN THE SEMICONDUCTOR INDUSTRY	
Application Type:	regular, utility	
Attorney Docket Number:	BUR920040086US1	
Correspondence address:		
Customer Number:	30449	*30449*
Inventors Information:		
<u>Inventor 1:</u>		
Applicant Authority Type:	Inventor	
Citizenship:	US	
Given Name:	Jed	
Middle Name:	H.	
Family Name:	Rankin	
City of Residence:	South Burlington	
State of Residence:	VT	
Country of Residence:	US	
Address-1 of Mailing Address:	211 Juniper Drive	
Address-2 of Mailing Address:		
City of Mailing Address:	South Burlington	
State of Mailing Address:	VT	
Postal Code of Mailing Address:	05403	
Country of Mailing Address:	US	
Phone:		
Fax:		
E-mail:		
<u>Inventor 2:</u>		
Applicant Authority Type:	Inventor	
Citizenship:	US	
Given Name:	Andrew	
Middle Name:	J.	
Family Name:	Watts	

City of Residence: Essex
State of Residence: VT
Country of Residence: US
Address-1 of Mailing Address: 20 Cedar Street
Address-2 of Mailing Address:
City of Mailing Address: Essex
State of Mailing Address: VT
Postal Code of Mailing Address: 05452
Country of Mailing Address: US
Phone:
Fax:
E-mail:

Attorney Information:

practitioner(s) at Customer Number:

30449 *30449*

as our attorney(s) or agent(s) to prosecute the application identified above, and to transact all business in the United States Patent and Trademark Office connected therewith.

Assignee 1:

Organization Name: International Business Machines Corporation
Address-1 of Mailing Address: New Orchard Road
Address-2 of Mailing Address:
City of Mailing Address: Armonk
State of Mailing Address: NY
Postal Code of Mailing Address: 10504
Country of Mailing Address: US
Phone:
Fax:
E-mail: